



WANSEMI
万芯半导体

WP4006KS3

Enhancement Mode N-Channel Power MOSFET

SOT23-3/NMOS/40V/ $\pm 20V$ /1.6V/6A/19m Ω

Rev0.6

40V, 19mΩ, 6A, Single N-Channel

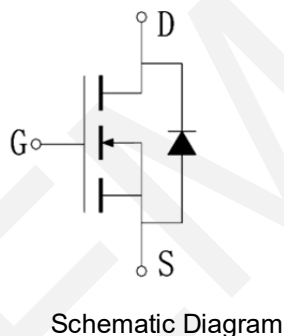
1.Features

- ◆ 40V MOSFET technology
- ◆ Low on-state resistance
- ◆ Fast switching
- ◆ $V_{GS} \pm 20V$

| V_{DS} | $R_{DS(on)}$ Typ. | I_D Max. |
|----------|-------------------|------------|
| 40V | 19mΩ @ 10V | 6A |
| | 25mΩ @ 4.5V | |

2.Applications

- ◆ Power Switching Application
- ◆ Load Switching



3.Package Marking and Ordering Information

| Part no. | Marking | Package | PCS/Reel | PCS/CTN. |
|-----------|---------|---------|----------|----------|
| WP4006KS3 | 4006K | SOT23-3 | 3,000 | 180,000 |

4.Absolute Max Ratings at $T_a=25^\circ\text{C}$ (Note1)

| Parameter | Symbol | Maximum | Units |
|---|-----------|-------------|------------------|
| Drain to Source Voltage | V_{DSS} | 40 | V |
| Gate to Source Voltage | V_{GSS} | ± 20 | V |
| Drain Current (DC) | I_D | 6 | A |
| Drain Current (Pulse), $PW \leq 300\mu s$ | I_{DP} | 24 | A |
| Total Dissipation | P_D | 1.3 | W |
| Junction Temperature | T_j | 150 | $^\circ\text{C}$ |
| Storage Temperature | T_{stg} | -55 to +150 | $^\circ\text{C}$ |

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

5. Thermal Resistance Ratings (Note 2)

| Parameter | Symbol | Value | Unit |
|---|-----------------|-------|----------------------|
| Thermal Resistance, Junction-to-Ambient | $R_{\theta JA}$ | 100 | $^{\circ}\text{C/W}$ |

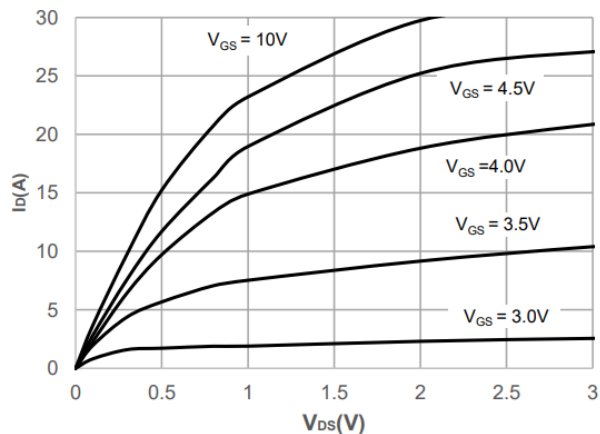
Note 2: When mounted on 1 inch square copper board $t \leq 10\text{sec}$ The value in any given application depends on the user's specific board design.

6. Electrical Characteristics at $T_a=25^{\circ}\text{C}$ (Note 3)

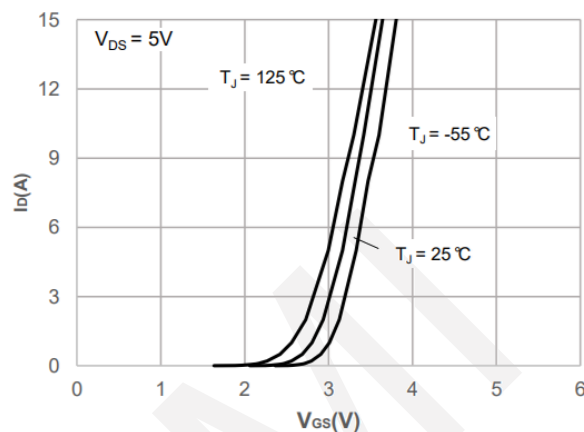
| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Units |
|--|---------------|--|------|------|-----------|------------------|
| Drain to Source Breakdown Voltage | $V_{(BR)DSS}$ | $I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$ | 40 | 42 | - | V |
| Zero-Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 40\text{V}$, $V_{GS} = 0\text{V}$ | - | - | 1 | μA |
| Gate to Source Leakage Current | I_{GSS} | $V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$ | - | - | ± 100 | nA |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}$, $I_{DS}=250\mu\text{A}$ | 1.0 | 1.6 | 2.5 | V |
| Static Drain to Source On-State Resistance | $R_{DS(on)}$ | $I_D = 5.5\text{A}$, $V_{GS} = 10\text{V}$ | - | 19 | 25 | $\text{m}\Omega$ |
| | | $I_D = 4.5\text{A}$, $V_{GS} = 4.5\text{V}$ | - | 25 | 35 | $\text{m}\Omega$ |
| Input Capacitance | C_{iss} | $V_{GS}=0\text{V}$, $V_{DS}=20\text{V}$, Frequency=1.0MHz | - | 536 | - | pF |
| Output Capacitance | C_{oss} | | - | 42 | - | pF |
| Reverse Transfer Capacitance | C_{rss} | | - | 33 | - | pF |
| Turn-ON Delay Time | $t_{d(on)}$ | $V_{DS} = 20\text{V}$, $I_D = 3\text{A}$ $V_{GS} = 10\text{V}$, $R_G = 3\Omega$ | - | 4 | - | ns |
| Rise Time | t_r | | - | 2 | - | ns |
| Turn-OFF Delay Time | $t_{d(off)}$ | | - | 15 | - | ns |
| Fall Time | t_f | | - | 2 | - | ns |
| Total Gate Charge | Q_g | $V_{DS} = 20\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 3\text{A}$ | - | 11 | - | nC |
| | Q_{gs} | | - | 2 | - | nC |
| | Q_{gd} | | - | 2 | - | nC |
| Diode Forward Voltage | V_{FSD} | $I_S = 6\text{A}$, $V_{GS} = 0$ | 0.4 | - | 1.4 | V |

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

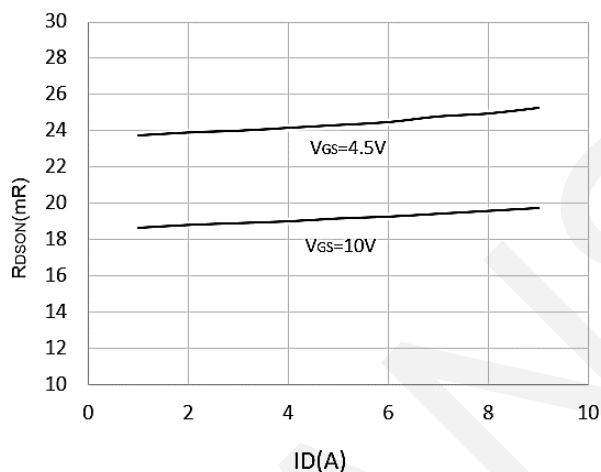
7. Typical Electrical and Thermal Characteristics



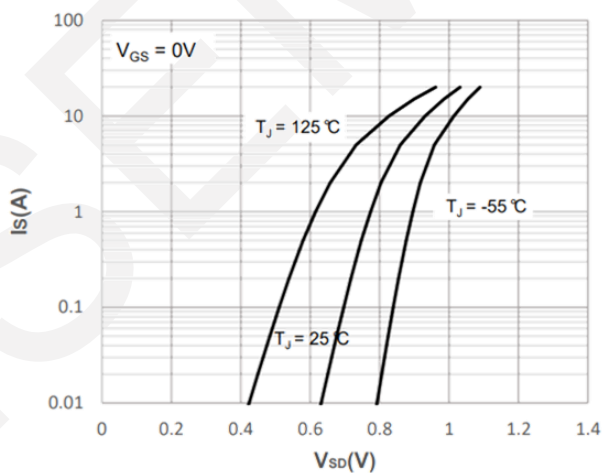
Output Characteristics



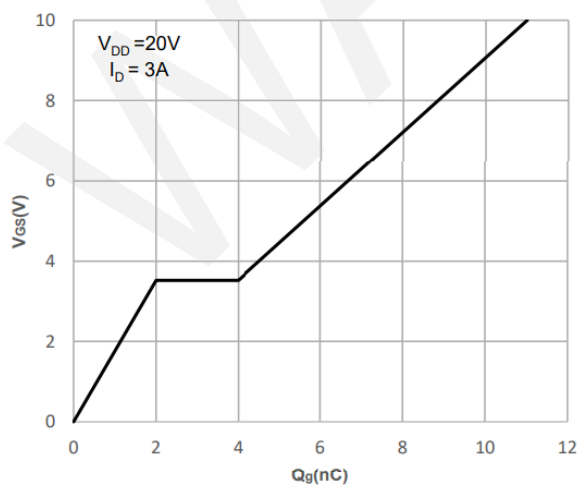
Typical Transfer Characteristics



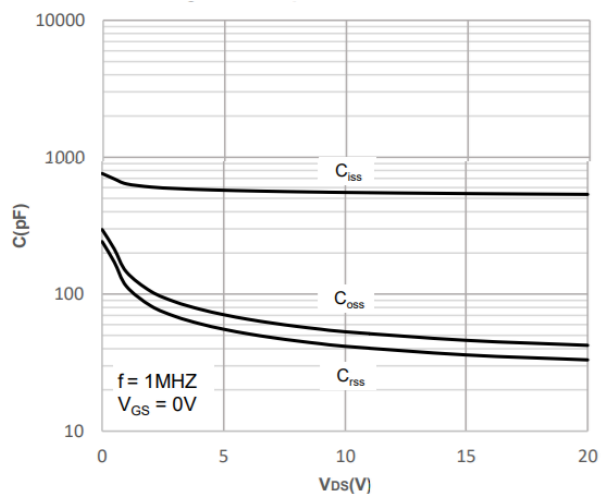
On-resistance vs. Drain Current



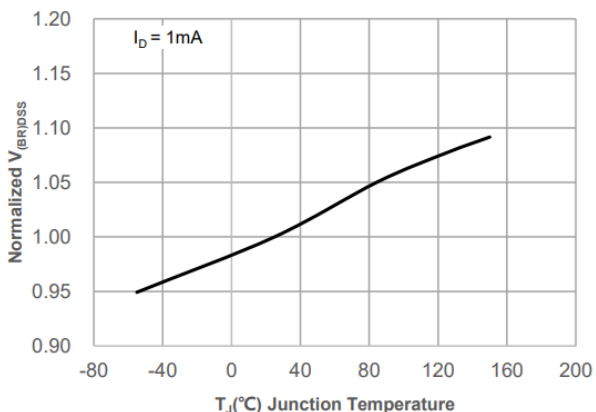
Body Diode Characteristics



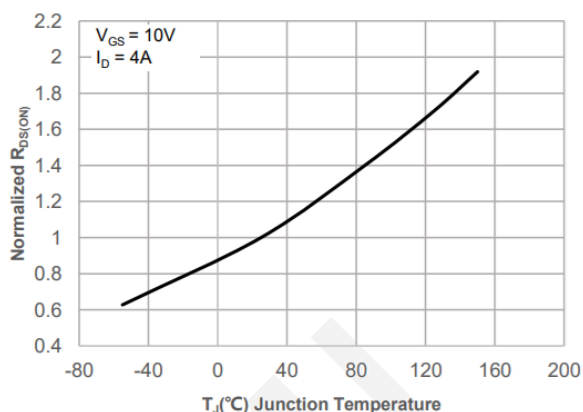
Gate Charge Characteristics



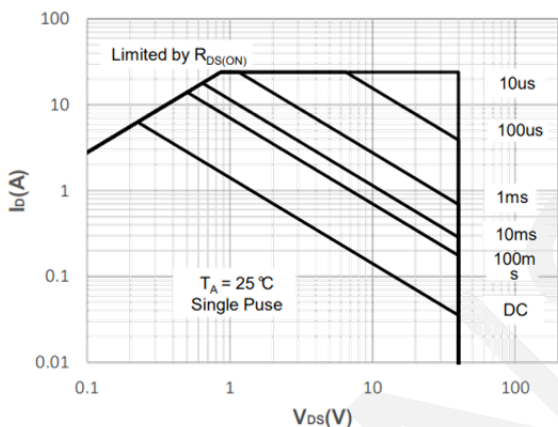
Capacitance Characteristics



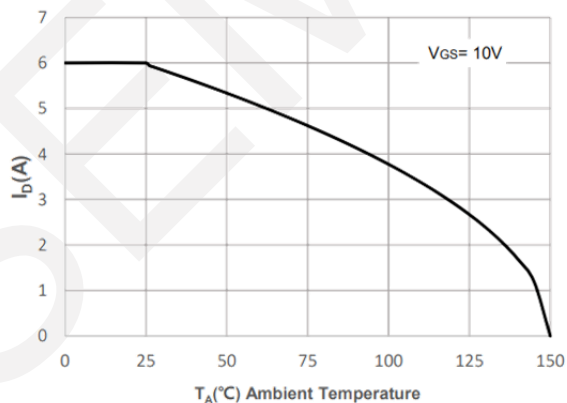
Normalized Breakdown Voltage vs.
Junction Temperature



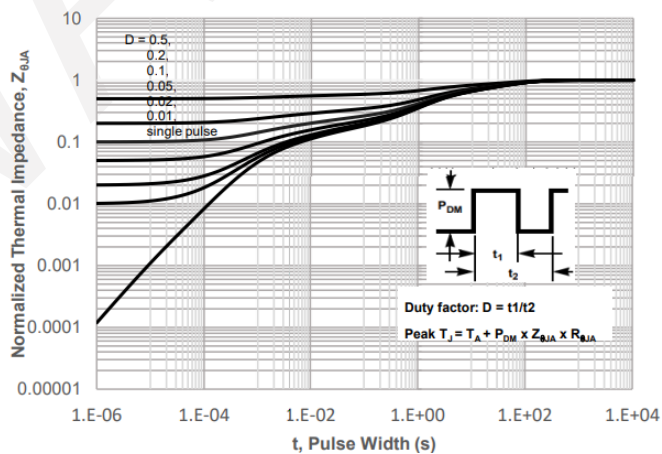
Normalized on Resistance vs.
Junction Temperature



Maximum Safe Operating Area



Maximum Continuous Drain Current vs.
Case Temperature

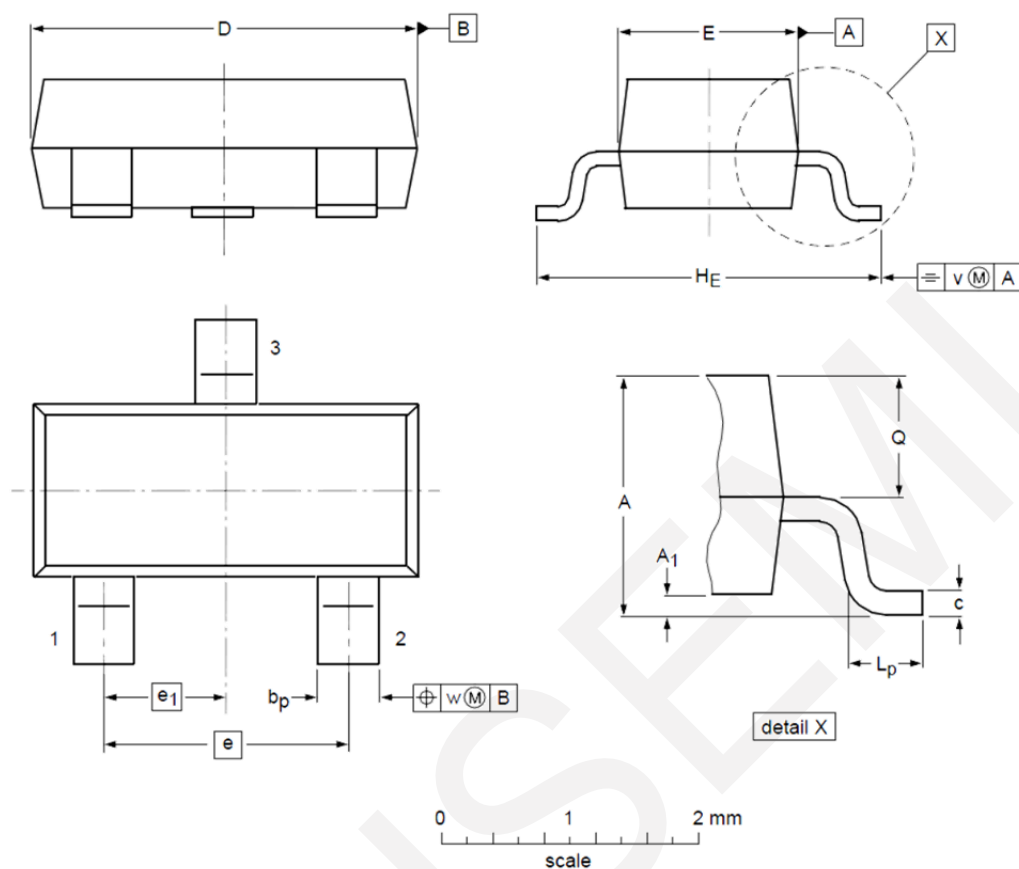


Maximum Effective Transient

Thermal Impedance, Junction-to-Case



8.Package Dimensions



DIMENSIONS (unit : mm)

| Symbol | Min | Typ | Max | Symbol | Min | Typ | Max |
|----------------|------|------|------|----------------|------|------|------|
| A | 1.00 | 1.17 | 1.30 | A ₁ | 0.01 | 0.05 | 0.10 |
| b _p | 0.35 | 0.39 | 0.50 | c | 0.10 | 0.20 | 0.26 |
| D | 2.70 | 2.90 | 3.10 | E | 1.30 | 1.58 | 1.70 |
| e | -- | 1.90 | -- | e ₁ | -- | 0.95 | -- |
| H _E | 2.50 | 2.78 | 3.00 | L _p | 0.20 | 0.32 | 0.60 |
| Q | 0.23 | 0.27 | 0.33 | v | -- | 0.20 | -- |
| w | -- | 0.20 | -- | | | | |

9. Important Notice

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